## Application/Control No. Applicant(s)/Patent Under Reexamination 09/541,185 HAYBALL ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Christian La Forgia 2131

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,529,499	03-2003	Doshi et al.	370/352
	В	US-6,442,147	08-2002	Mauger et al.	370/321
	С	US-6,430,154	08-2002	Hunt et al.	370/230.1
	D	US-2002/0093957	07-2002	Yazaki et al.	370/389
	Е	US-6,488,647	12-2002	Miura et al.	604/29
	F	US-6,718,380	04-2004	Mohaban et al.	709/223
	G	US-6,657,960	12-2003	Jeffries et al.	370/230.1
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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